

REMARKS

Claims 1-8 are pending in the application. Claims 2, 3, 6 and 7 have been amended and Claim 9 has been canceled. The filing fee has been calculated according to this amendment.

Claims 2, 3, 6 and 7 have been amended from a formal standpoint in accordance with the U. S. rules of practice and not for reasons relating to patentability. In formulating these amendments, the previous amendments to Claims 2 and 3 and the cancellation of Claim 9, were brought forth from the Article 34 amendment filed in the priority application PCT/GB00/00301.

Attached hereto is a marked-up version of the changes made to the claims by the current amendment.

Should the Examiner have any questions or comments regarding the amendments, the Examiner is invited to telephone the undersigned at the number listed below.

Respectfully submitted,



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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:	§	
Giles	§	Attorney Docket No.: 26114.4
	§	
Serial No.: US National Phase	§	International Filing Date:
of PCT/GB00/00301	§	02 February 2000
	§	
Filed: Herewith	§	
	§	
For: ION SOURCE FOR MASS ANALYSER	§	Priority Date Claimed:
		11 February 1999

REDLINE VERSION

2. (Amended) An ion source as claimed in claim 1, in which the interface chamber has a bend therein to introduce turbulence into the flow of gas and entrained sample ions as they flow along the said flow passage[.], the bend being formed between the said entrance aperture and the said exit aperture.

3. (Amended) An ion source as claimed in claim 1 [or claim 2], in which the interface chamber has a first passage adjacent the entrance aperture, and a second passage adjacent the exit aperture, the first and second passages communicating with each other and intersecting at an angle of approximately 90° to each other such that the intersection lies between the said entrance and exit apertures.

6. (Amended) An ion source as claimed in claim 3 [or claim 5], in which both the first passage and the second passage have a length substantially longer than their respective widths.

7. (Amended) An ion source as claimed in Claim 1 [any one of the preceding claims], in which the exit aperture comprises a frusto-conical hole formed within a block defining the interface chamber, the exit aperture further comprising a correspondingly frusto-conical insert member, the insert member having a bore therethrough to permit passage of sample ions and being coaxially aligned with the frusto-conical hole in the block.